

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/624,398 MATHEW ET AL.	
		Examiner	Art Unit Vuthe Siek	2825 Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0266115	12-2004	Chan et al.	438/284
	B	US-2005/0001216	01-2005	Adkisson et al.	257/066
	C	US-2005/0020020	01-2005	Collaert et al.	438/300
	D	US-2004/0117748	06-2004	Tester, David P.	716/011
	E	US-6,691,297	02-2004	Misaka et al.	716/21
	F	US-6,807,662	10-2004	Toublan et al.	716/21
	G	US-6,189,136	02-2001	Bothra, Subhas	716/21
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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